

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/621,324	CHEN ET AL.	
Examiner	Art Unit	
Ion N. Mooro	2616	

	SEAR	CHED	:
Class	Subclass	Date	Examiner
370	221-228	5/19/2007	INM
340	825.01	5/19/2007	INM
398	1-5,10,43	5/19/2007	INM
714	2-4,25	5/19/2007	INM
		•	
			!

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
	<u> </u>		

	DATE	EXMR
EAST (USPAT, USPGPUB, EPO)- see search history printout	3/26/2007	INM
Inventor and assignee search (see search history printout)	5/19/2007	INM